

LPM9013

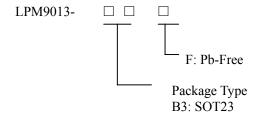
P-Channel Enhancement Mode Field Effect Transistor

General Description

The LPM9013 is the P-channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance.

These devices are particularly suited for low voltage application, notebook computer power management and other battery powered circuits where high-side switching.

Ordering Information



Features

- -20V/-2.6A,RDC(ON)= $125m\Omega(typ.)$ @VGS=-2.5V
- -20V/-3.0A, RDC(ON)= $98m\Omega(typ.)$ @VGS=-4.5V
- Super high density cell design for extremely low RDC(ON)
- SOT23 Package

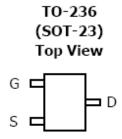
Applications

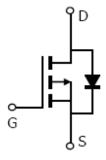
- ♦ Portable Media Players
- ♦ Cellular and Smart mobile phone
- ♦ LCD
- ♦ DSC Sensor
- ♦ Wireless Card

Marking Information

Please see website.

Pin Configurations





SOT23L(Top View)



Functional Pin Description

Absolute Maximum Ratings T _A =25°C unless otherwise noted						
Parameter		Symbol	Maximum	Units		
Drain-Source Voltage		V_{DS}	-20	V		
Gate-Source Voltage		V_{GS}	±8	V		
Continuous Drain	T _A =25°C		-3			
Current ^A	T _A =70°C	I_D	-2.4	Α		
Pulsed Drain Current ^B		I _{DM}	-15			
	T _A =25°C	D-	1.4	W		
Power Dissipation ^A	T _A =70°C	P _D	0.9	VV		
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 150	°C		

Thermal Characteristics							
Parameter	Symbol	Тур	Max	Units			
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{\theta JA}$	70	90	°C/W		
Maximum Junction-to-Ambient A	Steady-State	IN _θ JΑ	100	125	°C/W		
Maximum Junction-to-Lead ^C	Steady-State	$R_{\theta JL}$	63	80	°C/W		



Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
STATIC F	PARAMETERS					
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =-250μA, V _{GS} =0V	-20			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-16V, V _{GS} =0V			-1	μА
	Zero Cate Voltage Drain Carrent	T _J =	=55°C		-5	μΛ
I_{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±8V			±100	nΑ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_D=-250 \mu A$	-0.3	-0.55	-1	V
$I_{D(ON)}$	On state drain current	V _{GS} =-4.5V, V _{DS} =-5V	-15			Α
		V _{GS} =-4.5V, I _D =-3A		81	97	mΩ
D	Static Drain-Source On-Resistance	T _J =1	125°C	111	135	11152
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =-2.5V, I _D =-2.6A		108	130	mΩ
		V _{GS} =-1.8V, I _D =-1A		146	190	mΩ
g FS	Forward Transconductance	V _{DS} =-5V, I _D =-3A	4	7		S
V _{SD}	Diode Forward Voltage	I _S =-1A,V _{GS} =0V		-0.78	-1	V
Is	Maximum Body-Diode Continuous Cur	rent			-2	Α
DYNAMIC	PARAMETERS		•			
C _{iss}	Input Capacitance			540		pF
C _{oss}	Output Capacitance	V_{GS} =0V, V_{DS} =-10V, f=1MHz	:	72		pF
C _{rss}	Reverse Transfer Capacitance			49		pF
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz		12		Ω
SWITCHI	NG PARAMETERS		•			
Qg	Total Gate Charge			6.1		nC
Q _{gs}	Gate Source Charge	V _{GS} =-4.5V, V _{DS} =-10V, I _D =-3	SA	0.6		nC
Q_{gd}	Gate Drain Charge			1.6		nC
t _{D(on)}	Turn-On DelayTime			10		ns
t _r	Turn-On Rise Time	V _{GS} =-4.5V, V _{DS} =-10V, R _L =3	.3Ω,	12		ns
t _{D(off)}	Turn-Off DelayTime	R _{GEN} =3Ω		44		ns
t _f	Turn-Off Fall Time			22		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =-3A, dI/dt=100A/μs		21		ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =-3A, dI/dt=100A/μs		7.5		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the $t \le 10$ s thermal resistance rating. B: Repetitive rating, pulse width limited by junction temperature.

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C. The R $_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The SOA curve provides a single pulse rating.

FUNCTIONS AND RELIABILITY WITHOUT NOTICE.



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

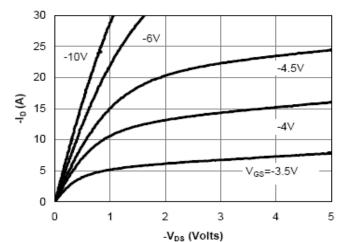


Fig 1: On-Region Characteristics (Note E)

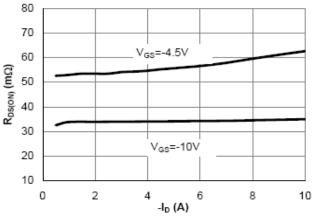


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

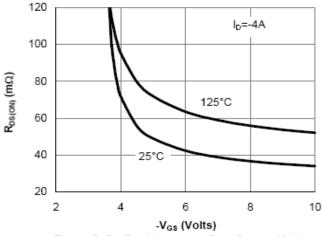


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

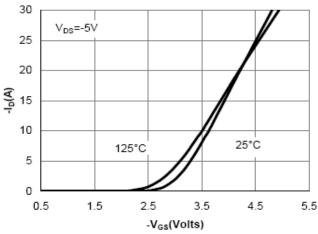


Figure 2: Transfer Characteristics (Note E)

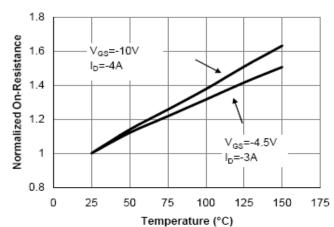


Figure 4: On-Resistance vs. Junction Temperature (Note E)

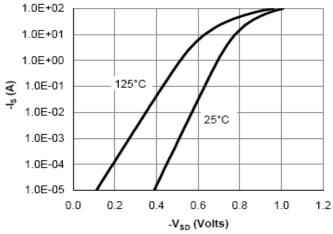


Figure 6: Body-Diode Characteristics (Note E)



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

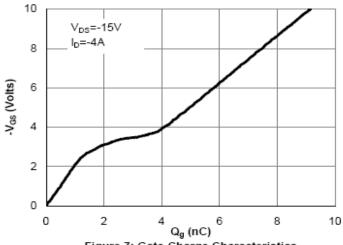


Figure 7: Gate-Charge Characteristics

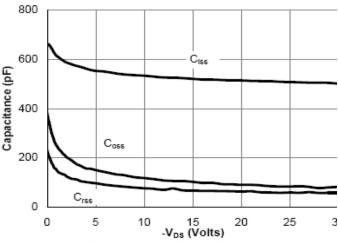


Figure 8: Capacitance Characteristics

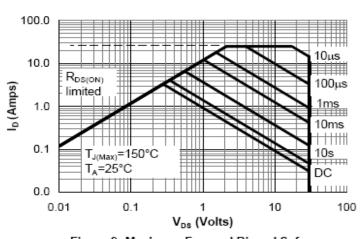


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

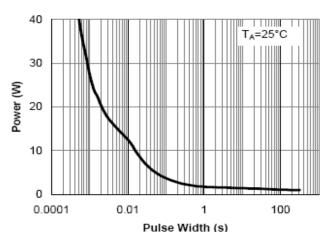


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

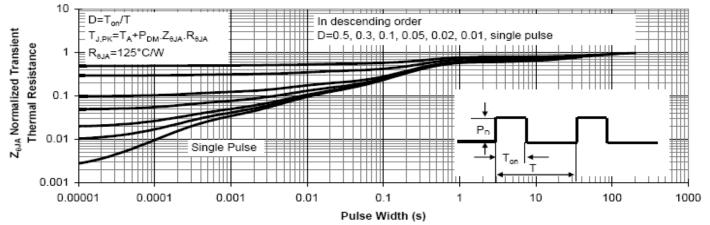
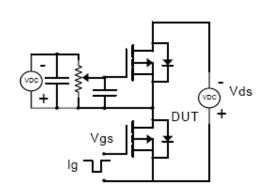
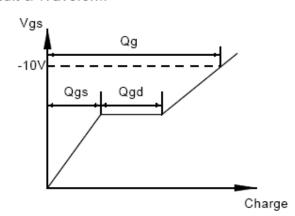


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

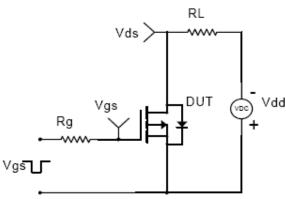


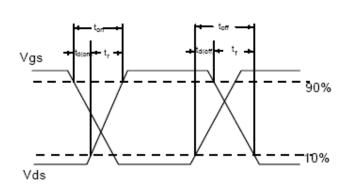
Gate Charge Test Circuit & Waveform



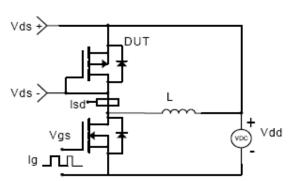


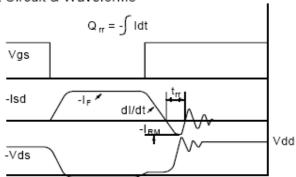
Resistive Switching Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms

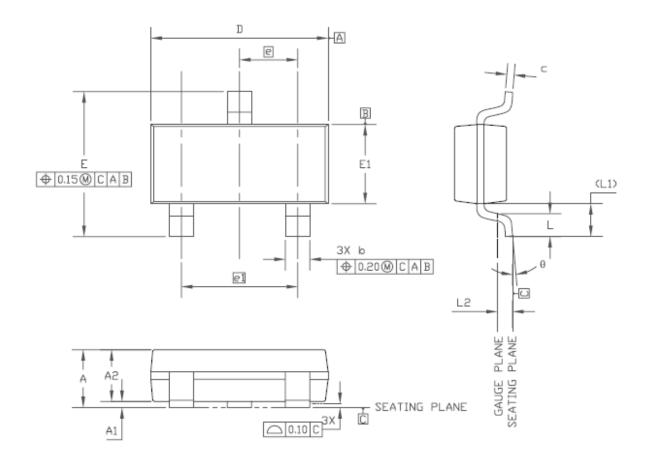




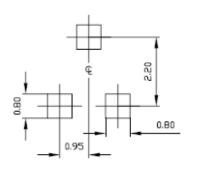


Packaging Information

SOT-23 STANDARD PACKAGE OUTLINE



RECOMMENDED LAND PATTERN



UNIT: mm

SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES			
31 MBOL3	MIN	NOM	MAX	MIN	NOM	MAX	
A	0.75		1.17	0.030		0.046	
A1	0.05	_	0.15	0.002	_	0.006	
A2	0.70	0.85	1.02	0.028	0.033	0.040	
b	0.30		0.50	0.012		0.020	
С	0.08		0.20	0.003		0.008	
D	2.80	2.90	3.04	0.110	0.114	0.120	
E	2.10	_	2.64	0.083	_	0.104	
E1	1.20	1.30	1.40	0.047	0.051	0.055	
e	0.95 BSC			0.037 BSC			
e1	1.90 BSC			0.075 BSC			
L	0.40	0.50	0.60	0.016	0.020	0.024	
L1	0.54 REF			0.021REF			
L2	0.25			0.010			
θ1	00		80	00		80	

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